

## N-Channel Enhancement Mode MOSFET

#### **Description**

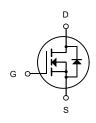
The NVTFS4C05NWFTAG uses advanced trench technology to provide excellent  $R_{\text{DS}(\text{ON})}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### DFN3X3-8L

#### **General Features**

 $V_{DS} = 30V I_{D} = 85A$ 

 $R_{DS(ON)}$  < 3.1 m $\Omega$  @  $V_{GS}$ =10V



N-Channel MOSFET

#### **Application**

Battery protection

Load switch

Uninterruptible power supply

#### **Package Marking and Ordering Information**

Product ID	Pack	Brand	Qty(PCS)
NVTFS4C05NWFTAG	DFN3X3-8L	HXY MOSFET	5000

#### Absolute Maximum Ratings (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter Rating		Units
VDS	Drain-Source Voltage	30	V
VGS	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	85	А
I <sub>D</sub> @T <sub>C</sub> =75 °C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	78	А
IDM	Pulsed Drain Current <sup>2</sup>	480	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	333	mJ
IAS	Avalanche Current	25	А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation⁴	88	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R <sub>θ</sub> JC	Thermal Resistance Junction-Case <sup>1</sup>	1.4	°C/W

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### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	H€			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C, I <sub>D</sub> =1mA				V/°C
В	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =20A		2.9	HÈ	0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =1Í A		HÈ	ΙĚ	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V -V 1 -250	1	1.Í	2.G	V
△V <sub>GS(th)</sub>	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=250uA$				mV/°C
	Drain Source Leakage Current	V <sub>DS</sub> =%'V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =%'V, V <sub>GS</sub> =0V , T <sub>J</sub> =100°C				uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS} = \pm 20V$ , $V_{DS} = 0V$			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =%'V , I <sub>D</sub> =20A				S
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz				Ω
Qg	Total Gate Charge			72		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> =15V , V <sub>GS</sub> =10V , I <sub>D</sub> =30A		46		nC
Q <sub>gd</sub>	Gate-Drain Charge			13		
T <sub>d(on)</sub>	Turn-On Delay Time	$V_{GS}$ =10V, $V_{DS}$ =15V, $I_{D}$ =30A, $R_{L}$ =3 $\Omega$		14		
Tr	Rise Time			18		
T <sub>d(off)</sub>	Turn-Off Delay Time			40		ns
T <sub>f</sub>	Fall Time			12		
C <sub>iss</sub>	Input Capacitance			4000		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		437	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			396		

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,4</sup>	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			85	Α
VsD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =30A , T <sub>J</sub> =25°C			1.2	V
t <sub>rr</sub>	Reverse Recovery Time	IF=30A , di/dt=100A/μs ,		48		nS
Qrr	Reverse Recovery Charge	T <sub>J</sub> =25°C		80		nC

<sup>1.</sup> Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature 2. EAS condition:  $T_J$  =25°C,  $V_{DD}$  =15V,  $V_G$  =10V,  $R_G$  =25 $\Omega$ , L=0.5mH,  $I_{AS}$ =25A 3. Pulse Test: Pulse Width≤300 $\mu$ s, Duty Cycle≤0.5%

#### **Typical Characteristics**

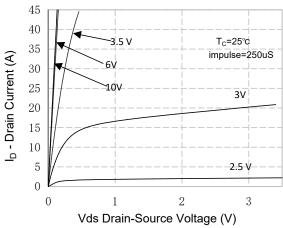


Figure 1. On-Region Characteristics

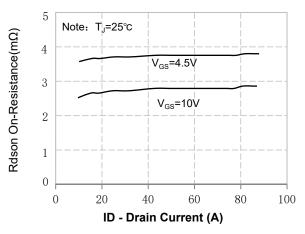


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

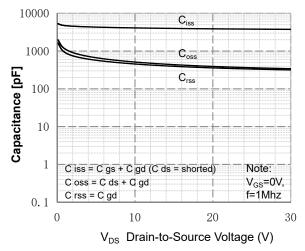


Figure 5. Capacitance Characteristics

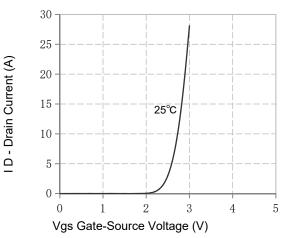


Figure 2. Transfer Characteristics

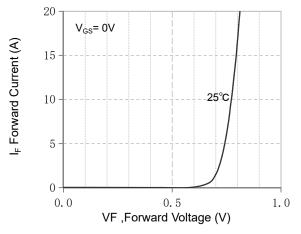


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

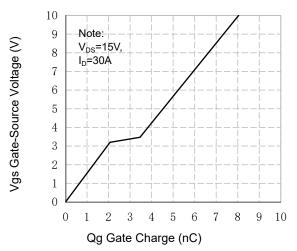
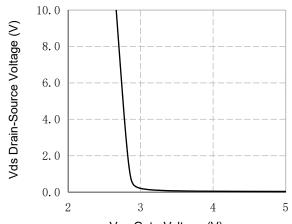
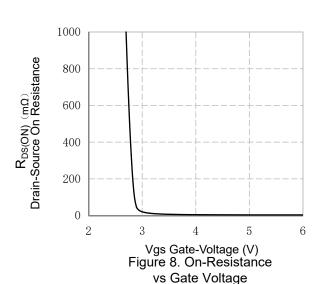


Figure 6. Gate Charge Characteristics



Vgs Gate-Voltage (V)
Figure 7. Vds Drain-Source Voltage
vs Gate Voltage



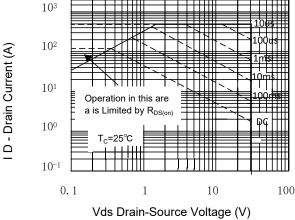
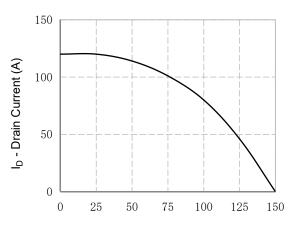


Figure 9. Maximum Safe Operating Area



T J -Junction Temperature(°C)
Figure 10. Maximum Continuous Drain
Current vs Temperature

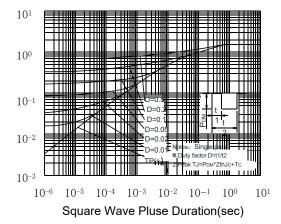
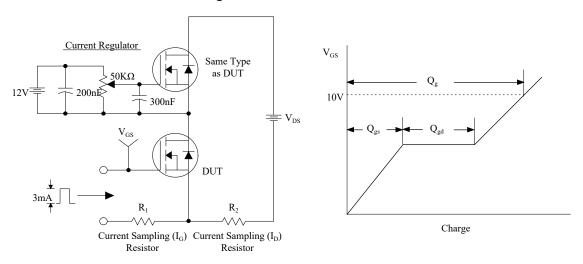


Figure 11. Transient Thermal Response Curve

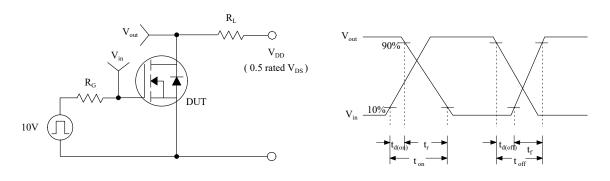


#### **Test Circuit**

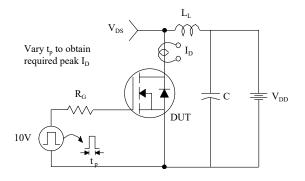
#### Gate Charge Test Circuit & Waveform

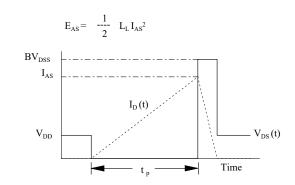


#### **Resistive Switching Test Circuit & Waveforms**



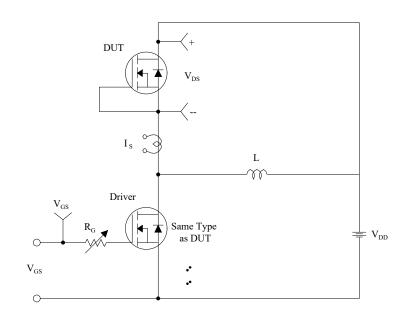
#### **Unclamped Inductive Switching Test Circuit & Waveforms**

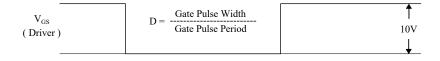


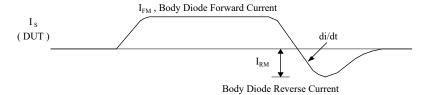


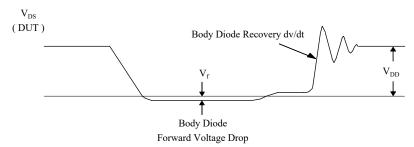
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#### Peak Diode Recovery dv/dt Test Circuit & Waveforms



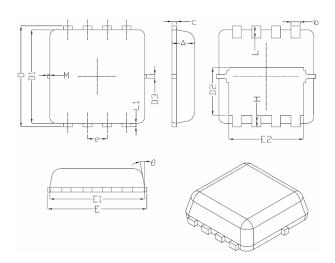








## **DFN3X3-8L Package Information**



Complete I	Dimensions In Millimeters			
Symbol	Min.	Nom.	Max.	
A	0.70	0.75	0.80	
b	0.25	0.30	0.35	
С	0.10	0.15	0.25	
D	3.25	3.35	3.45	
D1	3.00	3.10	3.20	
D2	1.48	1.58	1.68	
D3	-	0.13	-	
E	3.20	3.30	3.40	
E1	3.00	3.15	3.20	
E2	2.39	2.49	2.59	
е	0.65BSC			
Н	0.30	0.39	0.50	
L	0.30	0.40	0.50	
L1	-	0.13	-	
M	*	*	0.15	
θ		10°	12 <sup>°</sup>	

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